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TABLE OF CONTENTS

Features
Applications1
General Description 1
Functional Block Diagram 1
Revision History 2
Specifications
Absolute Maximum Ratings 4
Rate Sensitive Axis 4
ESD Caution 4
Pin Configuration and Function Descriptions
Typical Performance Characteristics

REVISION HISTORY

7/10—Rev. 0 to Rev. A	
Changed -40°C to +85°C to -40°C to +105°C Thr	oughout
Changes to General Description Section	1
Added Note 3 and Note 4, Table 1	3
Added Modifying the ADXRS652 Scale to Match the	
ADXRS620 Section	9
Changes to Ordering Guide	11

4/10—Revision 0: Initial Version

Theory of Operation	9
Setting Bandwidth	9
Temperature Output and Calibration	9
Modifying the ADXRS652 Scale to Match the ADXRS62	209
Calibrated Performance	9
ADXRS652 and Supply Ratiometricity	10
Null Adjustment	10
Self-Test Function	10
Continuous Self-Test	10
Outline Dimensions	11
Ordering Guide	11

SPECIFICATIONS

All minimum and maximum specifications are guaranteed. Typical specifications are not guaranteed.

 $T_A = -40^{\circ}$ C to $+105^{\circ}$ C, $V_S = AV_{CC} = V_{DD} = 5$ V, $V_{RATIO} = AV_{CC}$, angular rate $= 0^{\circ}$ /sec, bandwidth = 80 Hz ($C_{OUT} = 0.01 \mu$ F), $I_{OUT} = 100 \mu$ A, $\pm 1 g$, unless otherwise noted.

Table 1.

Parameter	Conditions	Min	Тур	Мах	Unit
SENSITIVITY ¹	Clockwise rotation is positive output		.,,,	max	
Measurement Range ²	Full-scale range over specifications range	±250 ³	±300		°/sec
Initial and Over Temperature	-40° C to $+105^{\circ}$ C 7.0 ⁴		mV/°/sec		
Temperature Drift⁵			±2		%
Nonlinearity	Best fit straight line		0.1		% of FS
NULL ¹					
Null	-40°C to +105°C		2.5		V
Linear Acceleration Effect	Any axis		0.1		°/sec/g
NOISE PERFORMANCE					
Rate Noise Density	$T_A \le 25^{\circ}C$		0.06		°/sec/√Hz
FREQUENCY RESPONSE					
Bandwidth ⁶		0.01		2500	Hz
Sensor Resonant Frequency			14.5		kHz
SELF-TEST ¹					
ST1 RATEOUT Response	ST1 pin from Logic 0 to Logic 1		-525		mV
ST2 RATEOUT Response	ST2 pin from Logic 0 to Logic 1		525		mV
ST1 to ST2 Mismatch ⁷		-5		+5	%
Logic 1 Input Voltage		3.3			V
Logic 0 Input Voltage				1.7	V
Input Impedance	To common	40	50	100	kΩ
TEMPERATURE SENSOR ¹					
Vout at 25°C	$Load = 10 M\Omega$		2.5		V
Scale Factor ⁸	25° C, V _{RATIO} = 5 V		9		mV/°C
Load to Vs			25		kΩ
Load to Common			25		kΩ
TURN-ON TIME	Power on to $\pm \frac{1}{2}^{\circ}$ /sec of final			50	ms
OUTPUT DRIVE CAPABILITY					
Current Drive	For rated specifications			200	μΑ
Capacitive Load Drive				1000	pF
POWER SUPPLY					
Operating Voltage (V _S)		4.75	5.00	5.25	V
Quiescent Supply Current			3.5	4.5	mA
TEMPERATURE RANGE					
Specified Performance		-40		+105	°C

 $^{\rm 1}$ Parameter is linearly ratiometric with V_{RATIO}

² Measurement range is the maximum range possible, including output swing range, initial offset, sensitivity, offset drift, and sensitivity drift at 5 V supplies.

³ See the Theory of Operation section to configure the sensitivity to match the ADXRS620 ±300°/sec minimum range.

⁴ See the Theory of Operation section to configure the sensitivity to match the ADXRS620 6 mV/°/sec scale.

⁵ From +25°C to -40°C or +25°C to +105°C.

⁶ Adjusted by external capacitor, C_{OUT}. Reducing bandwidth below 0.01 Hz does not result in further noise improvement.

⁷ Self-test mismatch is described as (ST2 + ST1)/((ST2 - ST1)/2).

⁸ Scale factor for a change in temperature from 25°C to 26°C. V_{TEMP} is ratiometric to V_{RATIO}. See the Temperature Output and Calibration section for more information.

ABSOLUTE MAXIMUM RATINGS

Table 2.

Parameter	Rating
Acceleration (Any Axis, 0.5 ms)	
Unpowered	2000 g
Powered	2000 g
V _{DD} , AV _{CC}	–0.3 V to +6.0 V
Vratio	AVcc
ST1, ST2	AVcc
Output Short-Circuit Duration (Any Pin to Common)	Indefinite
Operating Temperature Range	–55°C to +125°C
Storage Temperature Range	–65°C to +150°C

Stresses above those listed under the Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Drops onto hard surfaces can cause shocks of greater than 2000 *g* and can exceed the absolute maximum rating of the device. Care should be exercised in handling to avoid damage.

RATE SENSITIVE AXIS

This is a Z-axis rate-sensing device (also called a yaw ratesensing device). It produces a positive going output voltage for clockwise rotation about the axis normal to the package top, that is, clockwise when looking down at the package lid.

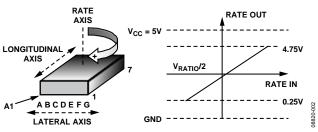


Figure 2. RATEOUT Signal Increases with Clockwise Rotation

ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

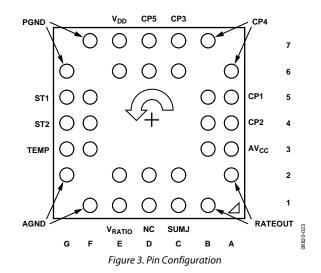


Table 3.	Pin	Function	Descriptions
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Pin No.	Mnemonic	Description	
6D, 7D	CP5	HV Filter Capacitor, 0.1 μF.	
6A, 7B	CP4	Charge Pump Capacitor, 22 nF.	
6C, 7C	CP3	Charge Pump Capacitor, 22 nF.	
5A, 5B	CP1	Charge Pump Capacitor, 22 nF.	
4A, 4B	CP2	Charge Pump Capacitor, 22 nF.	
3A, 3B	AVcc	Positive Analog Supply.	
1B, 2A	RATEOUT	Rate Signal Output.	
1C, 2C	SUMJ	Output Amp Summing Junction.	
1D, 2D	NC	No Connection.	
1E, 2E	V _{RATIO}	Reference Supply for Ratiometric Output.	
1F, 2G	AGND	Analog Supply Return.	
3F, 3G	TEMP	Temperature Voltage Output.	
4F, 4G	ST2	Self-Test for Sensor 2.	
5F, 5G	ST1	Self-Test for Sensor 1.	
6G, 7F	PGND	Charge Pump Supply Return.	
6E, 7E	V _{DD}	Positive Charge Pump Supply.	

TYPICAL PERFORMANCE CHARACTERISTICS

N > 1000 for all typical performance plots, unless otherwise noted.

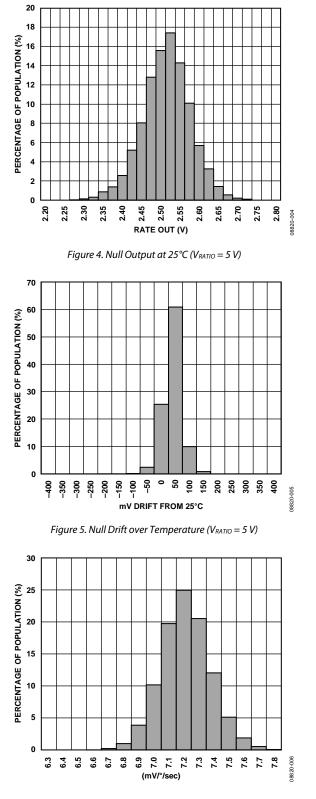


Figure 6. Sensitivity at $25^{\circ}C$ (V_{RATIO} = 5 V)

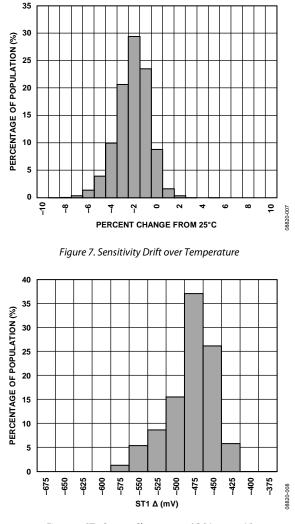
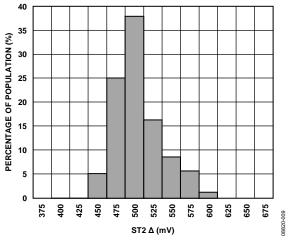
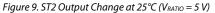


Figure 8. ST1 Output Change at $25^{\circ}C$ ($V_{RATIO} = 5 V$)





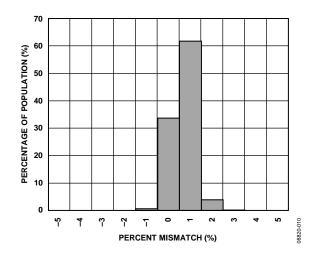


Figure 10. Self-Test Mismatch at $25^{\circ}C$ (V_{RATIO} = 5 V)

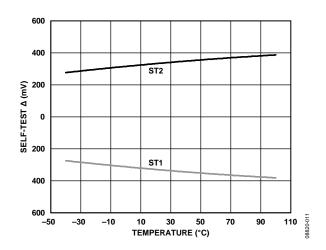


Figure 11. Typical Self-Test Change over Temperature

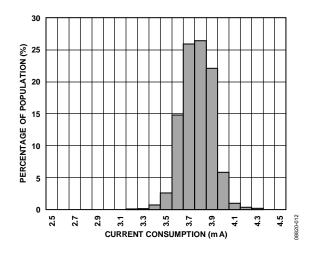


Figure 12. Current Consumption at $25^{\circ}C$ (V_{RATIO} = 5 V)

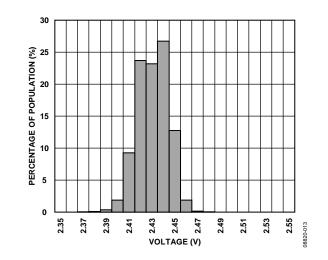


Figure 13. VTEMP Output at 25°C (VRATIO = 5 V)

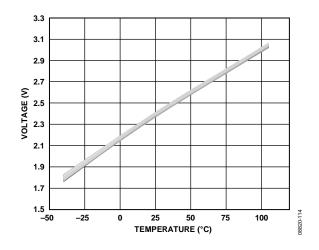


Figure 14. V_{TEMP} Output over Temperature, 256 Parts (V_{RATIO} = 5 V)

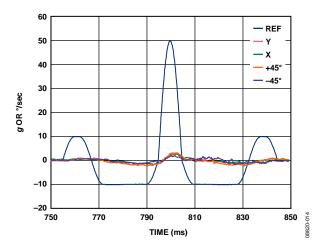
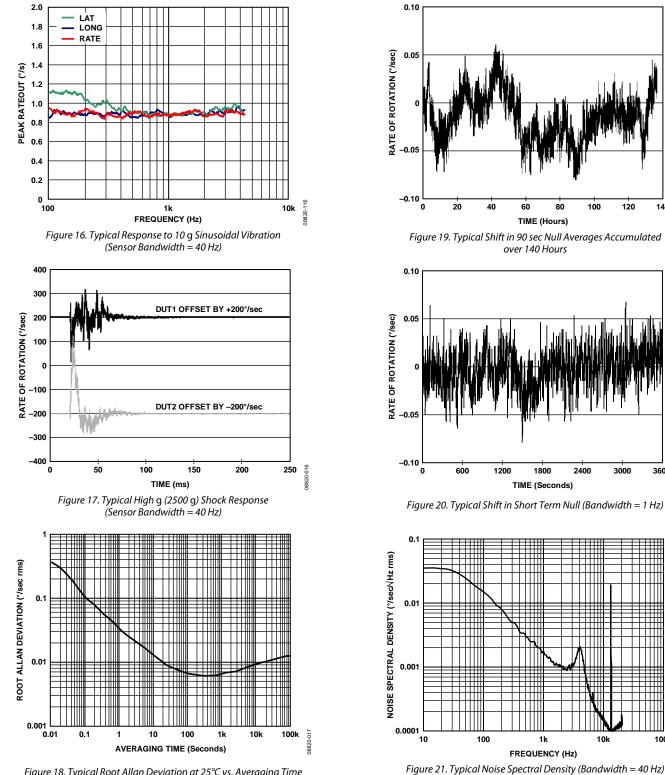


Figure 15. g and $g \times g$ Sensitivity for a 50 g, 10 ms Pulse



100

2400

10k

3000

3600

100k 08820-02 U

08820-019

120

140 8820-018

Figure 18. Typical Root Allan Deviation at 25°C vs. Averaging Time

THEORY OF OPERATION

The ADXRS652 operates on the principle of a resonator gyro. Two polysilicon sensing structures each contain a dither frame that is electrostatically driven to resonance, producing the necessary velocity element to produce a Coriolis force during angular rate. At two of the outer extremes of each frame, orthogonal to the dither motion, are movable fingers that are placed between fixed pickoff fingers to form a capacitive pickoff structure that senses Coriolis motion. The resulting signal is fed to a series of gain and demodulation stages that produce the electrical rate signal output. The dual-sensor design rejects external *g*-forces and vibration. Fabricating the sensor with the signal conditioning electronics preserves signal integrity in noisy environments.

The electrostatic resonator requires 18 V to 20 V for operation. Because only 5 V are typically available in most applications, a charge pump is included on chip. If an external 18 V to 20 V supply is available, the two capacitors on CP1 to CP4 can be omitted, and this supply can be connected to CP5 (Pin 6D, Pin 7D). CP5 should not be grounded when power is applied to the ADXRS652. No damage occurs, but under certain conditions, the charge pump may fail to start up after the ground is removed without first removing power from the ADXRS652.

SETTING BANDWIDTH

External Capacitor C_{OUT} is used in combination with the onchip R_{OUT} resistor to create a low-pass filter to limit the bandwidth of the ADXRS652 rate response. The -3 dB frequency set by R_{OUT} and C_{OUT} is

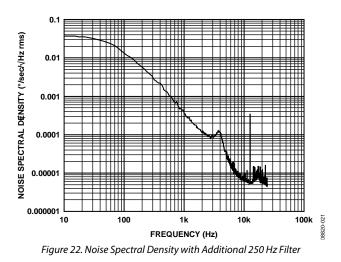
$$f_{OUT} = 1/(2 \times \pi \times R_{OUT} \times C_{OUT})$$

and can be well controlled because R_{OUT} has been trimmed during manufacturing to be 180 k $\Omega \pm$ 1%. Any external resistor applied between the RATEOUT pin (1B, 2A) and SUMJ pin (1C, 2C) results in

 $R_{OUT} = (180 \text{ k}\Omega \times R_{EXT})/(180 \text{ k}\Omega + R_{EXT})$

In general, an additional filter (in either hardware or software) is added to attenuate high frequency noise arising from demodulation spikes at the 14 kHz resonant frequency of the gyro. The noise spikes at 14 kHz can be clearly seen in the power spectral density curve, shown in Figure 21. Normally, this additional filter corner frequency is set to greater than five times the required bandwidth to preserve good phase response.

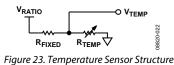
Figure 22 shows the effect of adding a 250 Hz filter to the output of an ADXRS652 set to 40 Hz bandwidth (as shown in Figure 21). High frequency demodulation artifacts are attenuated by approximately 18 dB.



TEMPERATURE OUTPUT AND CALIBRATION

It is common practice to temperature-calibrate gyros to improve their overall accuracy. The ADXRS652 has a temperature proportional voltage output that provides input to such a calibration method. The temperature sensor structure is shown in Figure 23. The temperature output is characteristically nonlinear, and any load resistance connected to the TEMP output results in decreasing the TEMP output and its temperature coefficient. Therefore, buffering the output is recommended.

The voltage at TEMP (3F, 3G) is nominally 2.5 V at 25°C, and $V_{RATIO} = 5$ V. The temperature coefficient is ~9 mV/°C at 25°C. Although the TEMP output is highly repeatable, it has only modest absolute accuracy.



MODIFYING THE ADXRS652 SCALE TO MATCH THE ADXRS620

The ADXRS652 scale factor can be modified to match the 6 mV/°/sec scale factor of the ADXRS620 by adding a single 1.07 M Ω resistor between the RATEOUT and SUMJ. No other performance characteristics are affected by adding this resistor.

CALIBRATED PERFORMANCE

Using a three-point calibration technique, it is possible to calibrate the ADXRS652 null and sensitivity drift to an overall accuracy of nearly 200°/hour. An overall accuracy of 40°/hour or better is possible using more points. Limiting the bandwidth of the device reduces the flat-band noise during the calibration process, improving the measurement accuracy at each calibration point.

ADXRS652 AND SUPPLY RATIOMETRICITY

The ADXRS652 RATEOUT and TEMP signals are ratiometric to the V_{RATIO} voltage; that is, the null voltage, rate sensitivity, and temperature outputs are proportional to V_{RATIO} . So the ADXRS652 is most easily used with a supply-ratiometric analog-to-digital converter, which results in self-cancellation of errors due to minor supply variations. There is some small error due to nonratiometric behavior. Typical ratiometricity error for null, sensitivity, self-test, and temperature output is outlined in Table 4.

Note that V_{RATIO} must never be greater than AV_{CC} .

Table 4. Ration	netricity Error for	Various Parameters

Parameter	$V_s = V_{RATIO} = 4.85 V$	$V_s = V_{RATIO} = 5.15 V$	
ST1			
Mean	0.3%	0.09%	
Sigma	0.21%	0.19%	
ST2			
Mean	-0.15%	-0.2%	
Sigma	0.22%	0.2%	
Null			
Mean	-0.3%	-0.05%	
Sigma	0.2%	0.08%	
Sensitivity			
Mean 0.003%		-0.25%	
Sigma	Sigma 0.06% 0.06%		
V _{TEMP}			
Mean	-0.2%	-0.04%	
Sigma	0.05%	0.06%	

NULL ADJUSTMENT

The nominal 2.5 V null is for a symmetrical swing range at RATEOUT (1B, 2A). However, a nonsymmetric output swing may be suitable in some applications. Null adjustment is possible by injecting a suitable current to SUMJ (1C, 2C). Note that supply disturbances may reflect some null instability. Digital supply noise should be avoided, particularly in this case.

SELF-TEST FUNCTION

The ADXRS652 includes a self-test feature that actuates each of the sensing structures and associated electronics in the same manner, as if subjected to angular rate. It is activated by standard logic high levels applied to Input ST1 (5F, 5G), Input ST2 (4F, 4G), or both. ST1 causes the voltage at RATEOUT to change about –0.5 V, and ST2 causes an opposite change of +0.5 V. The self-test response follows the viscosity temperature dependence of the package atmosphere, approximately 0.25%/°C.

Activating both ST1 and ST2 simultaneously is not damaging. ST1 and ST2 are fairly closely matched (\pm 5%), but actuating both simultaneously may result in a small apparent null bias shift proportional to the degree of self-test mismatch.

ST1 and ST2 are activated by applying a voltage equal to V_{RATIO} to the ST1 pin and the ST2 pin. The voltage applied to ST1 and ST2 must never be greater than AV_{CC} .

CONTINUOUS SELF-TEST

The on-chip integration of the ADXRS652 gives it higher reliability than is obtainable with any other high volume manufacturing method. Also, it is manufactured under a mature BiMOS process that has field-proven reliability. As an additional failure detection measure, power-on self-test can be performed. However, some applications may warrant continuous self-test while sensing rate. Details outlining continuous self-test techniques are also available in the AN-768 Application Note.

OUTLINE DIMENSIONS

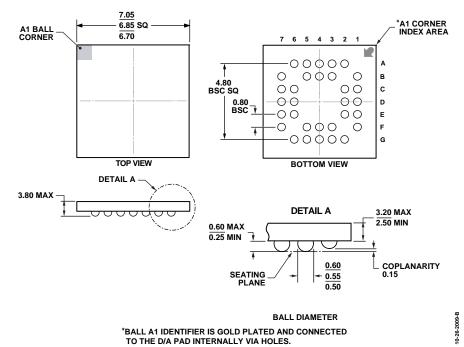


Figure 24. 32-Lead Ceramic Ball Grid Array [CBGA] (BC-32-3) Dimensions shown in millimeters

ORDERING GUIDE

Model ¹	Temperature Range	Package Description	Package Option
ADXRS652BBGZ	–40°C to +105°C	32-Lead Ceramic Ball Grid Array [CBGA]	BC-32-3
ADXRS652BBGZ-RL	–40°C to +105°C	32-Lead Ceramic Ball Grid Array [CBGA]	BC-32-3
ADXRS652BBGZ-RL7	–40°C to +105°C	32-Lead Ceramic Ball Grid Array [CBGA]	BC-32-3
EVAL-ADXRS652Z		Evaluation Board	

¹ Z = RoHS Compliant Part.

NOTES

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Rev. A | Page 12 of 12